

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
890050.443APPLICATION NO.  
10/684,981INFORMATION DISCLOSURE STATEMENT  
(Use several sheets if necessary)APPLICANTS  
Hiroyasu Inoue et al.FILING DATE  
October 14, 2003GROUP ART UNIT  
1756

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>W</i>	AA	3,959,799	05/28/76	Gambino et al.	346	135	
<i>W</i>	AB	4,357,616	11/02/82	Terao et al.	346	135.1	
<i>W</i>	AC	4,477,819	10/16/84	Lee et al.	346	76 L	
<i>W</i>	AD	4,587,533	05/06/86	Nakane et al.	346	135.1	
<i>W</i>	AE	4,647,947	03/03/87	Takeoka	346	135.1	
<i>W</i>	AF	4,670,345	06/02/87	Morimoto	428	411.1	
<i>W</i>	AG	4,771,413	09/13/88	Nago	369	109	
<i>W</i>	AH	4,772,897	09/28/88	Ohkawa	346	135.1	
<i>W</i>	AI	5,185,733	02/09/93	Finkelstein et al.	369	54	
<i>W</i>	AJ	5,194,363	03/16/93	Yoshioka et al.	430	271	

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>W</i>	AK	57-022095	02/04/82	JP (Abstract in English only)		
<i>W</i>	AL	57-027788	02/15/82	JP (+ Abstract in English)		
<i>W</i>	AM	58-220794	12/22/83	JP (+ Abstract in English)		
<i>W</i>	AN	59-225992	12/19/84	JP (+ Abstract in English)		
<i>W</i>	AO	60-160036	08/21/85	JP (+ Abstract in English)		
<i>W</i>	AP	0 068 801 B1	09/18/86	EP		

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>W</i>	AQ	Inoue, H., et al., "Inorganic Write-Once Disc for High Speed Recording," Jpn. J. Appl. Phys. Vol. 42, part 1, no. 2B, pp. 1059-1061, February 2003.
<i>W</i>	AR	Kikukawa, T., et al., "Rigid Bubble Pit Formation and Huge Signal Enhancement in Super-Resolution Near-Field Structure Disk with Platinum-oxide Layer," Applied Physics Letters 81(25):4697-4699.











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




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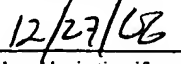
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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	BA	5,208,088	05/04/93	Tominaga et al.	428	64	
	BB	5,297,132	03/22/94	Takano et al.	369	284	
	BC	5,325,351	06/28/94	Uchiyama et al.	369	275.1	
	BD	5,401,330	03/28/95	Saito et al.	136	259	
	BE	5,414,451	05/09/95	Sugiyama et al.	347	258	
	BF	5,458,941	10/11/95	Hintz	428	64.4	
	BG	5,511,057	04/23/96	Holtslag et al.	369	94	
	BH	5,583,643	12/18/96	Gass et al.	356	445	
	BI	5,656,370	08/12/97	Murakami et al.	428	332	
	BJ	5,818,808	10/06/98	Takada et al.	369	116	

FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
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	BK	62-16193	01/24/87	JP (+ Abstract in English)		
	BL	62-28941	02/06/87	JP (+ Abstract in English)		
	BM	62-204442	09/09/87	JP (+English Abstract only)		
	BN	62-245545	10/26/87	JP (+ Abstract in English)		
	BO	37 41 910 A1	06/23/88	DE (+ Abstract in English)		

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
	BP	Kim, J., et al., "50nm Signal Writing and Retrieve by PtOx Type S-RENS Disk in Blue Laser Optical System," Extended Abstracts, 63rd Meeting The Japan Society of Applied Physics, Abstract No. 27a-YD-4, p. 1005, September 2002.
	BQ	Kim, J., et al., "Random Pattern Signal Characteristics of Super-RENS Disk at Blue Laser System," Technical Digest of Optical Data Storage Topical Meeting, pp. 273-275, 2004.

EXAMINER 	DATE CONSIDERED 
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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>W</i>	CA	5,875,169	02/23/99	Hatwar	369	272	
<i>W</i>	CB	5,912,104	06/15/99	Hirotsune et al.	430	270.13	
<i>W</i>	CC	5,948,496	09/01/99	Kinoshita et al.	428	64.1	
<i>W</i>	CD	5,949,747	09/01/99	Miyashita et al.	369	54	
<i>W</i>	CE	5,958,649	09/28/99	Hirotsune et al.	430	270.13	
<i>W</i>	CF	6,033,752	03/01/00	Suzuki et al.	428	64.1	
<i>W</i>	CG	6,096,399	08/01/00	Yoshinari et al.	428	64.1	
<i>W</i>	CH	6,111,851	08/29/00	Ohki et al.	369	286	
<i>W</i>	CI	6,143,469	11/07/00	Ohta et al.	430	270.13	
<i>W</i>	CJ	6,187,406	02/13/01	Ichihara et al.	428	64.1	

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
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<i>W</i>	CK	63-299984	12/01/88	JP (+ Abstract in English)		
<i>W</i>	CL	01-158633	06/21/89	JP (+ Abstract in English)		
<i>W</i>	CM	1-270528	10/27/89	JP (+ Abstract in English)		
<i>W</i>	CN	2-152029	06/12/90	JP (+ Abstract in English)		
<i>W</i>	CO	3-49054	03/01/91	JP (+ Abstract in English)		
<i>W</i>	CP	0 474 311 A1	03/11/92	EP		
<i>W</i>	CQ	4-86283	03/18/92	JP (+ Abstract in English)		

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>W</i>	CR	Kim, J., et al., "Signal Characteristics of Super-RENS Disk at Blue Laser System," Technical Digest of International Symposium on Optical Memory, Fr-J-01:264-265, 2003.
<i>W</i>	CS	Kim, J., et al., "Super-Resolution by Elliptical Bubble Formation with PtOx and AgInSbTe Layers," Applied Physics Letters, 83(9):1701-1703, September 1, 2003.

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12/27/06

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<b>U.S. PATENT DOCUMENTS</b>							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>he</i>	DA	6,210,860	04/08/01	Fukano et al.	430	270.12	
<i>he</i>	DB	6,221,455	04/24/01	Yasuda et al	428	64.1	
<i>nr</i>	DC	6,231,945	05/15/01	Miyamoto et al.	428	64.1	
<i>he</i>	DD	6,254,966	07/03/01	Kondo	428	156	
<i>nr</i>	DE	6,266,299	07/24/01	Oshima et al.	369	13	
<i>he</i>	DF	6,278,680	08/21/01	Miyauchi et al.	369	112.01	
<i>nr</i>	DG	6,355,326	03/12/02	Lee et al.	428	64.1	
<i>he</i>	DH	6,404,712	06/11/02	Lee et al.	369	47.53	
<i>nr</i>	DI	6,404,713	06/11/02	Ueki	369	47.53	
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
<i>nr</i>	DJ	4-226785	08/17/92	JP (+ Abstract in English)			
<i>nr</i>	DK	4-298389	10/22/92	JP (+ Abstract in English)			
<i>nr</i>	DL	0 350 078 B1	03/09/94	EP			
<i>he</i>	DM	6-171236	06/21/94	JP (+ Abstract in English)			
<i>nr</i>	DN	6-243507	09/02/94	JP (+ Abstract in English)			
<i>he</i>	DO	6-262854	09/20/94	JP (+ Abstract in English)			
<b>OTHER PRIOR ART</b> (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>he</i>	DP	Narumi, K. et al., "45GB Rewritable Dual-Layer Phase-Change Optical Disk With A Transmittance Balanced Structure", Technical Digest, International Symposium on Optical Memory 2001, Grand Hotel, Taipei, Taiwan, October 16-19, 2001, pages 202 & 203.					
<i>he</i>	DQ	Yoshii, K., et al., "Investigation of Hole Formation on Cr/Al, Si/Al, and C/Al Bilayer Films by Laser Beam Irradiation," <i>Journal of Applied Physics</i> 55(1):223-229, January 1, 1984.					
EXAMINER				DATE CONSIDERED			
				12/27/02			
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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	EA	6,416,837	07/09/02	Kojima et al.	428	64.1	
	EB	6,511,788	01/28/03	Yasuda et al.	430	270.13	
	EC	6,551,679	04/22/03	Kuroda et al.	428	64.1	
	ED	6,608,799	08/19/03	Hozumi	369	13.26	
	EE	6,611,481	08/26/03	Koishi et al.	369	47.53	
	EF	6,636,477	10/21/03	Miyamoto et al.	369	286	
	EG	6,656,559	12/02/03	Mizushima et al.	428	64.1	
	EH	6,660,451	12/09/03	Sakaue et al.	430	270.13	
	EI	6,670,014	12/30/03	Nishihara et al.	428	64.1	
	EJ	6,788,635	09/07/04	Aratani et al.	369	100	

FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
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	EK	6-274922	09/30/94	JP (+ Abstract in English)		
	EL	7-235465	09/05/95	JP (+ Abstract in English)		
	EM	8-124165	05/17/96	JP (+ Abstract in English)		
	EN	9-7176	01/10/97	JP (+ Abstract in English)		
	EO	0 822 543 A1	02/04/98	EP		
	EP	10-76755	03/24/98	JP (+ Abstract in English)		
	EQ	10-134919	05/22/98	JP		
	ER	0 978 831 A2	02/09/00	EP		

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
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EXAMINER	DATE CONSIDERED 12/27/08
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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>he</i>	FA	6,791,926	09/14/04	Furumiya et al.	369	53.13	
<i>m</i>	FB	6,805,935	10/19/04	Ashida et al.	428	64.1	
<i>he</i>	FC	6,807,142	10/19/04	Nagata et al.	369	275.2	
<i>he</i>	FD	6,841,218	01/11/05	Hosoda et al.	428	64.1	
<i>he</i>	FE	6,929,840	08/16/05	Hosoda et al.	428	64.1	
<i>he</i>	FF	6,982,111	01/03/06	Mizushima et al.	428	64.1	
<i>he</i>	FG	6,996,055	02/07/06	Mishima et al.	369	283	
<i>he</i>	FH	7,002,887	02/21/06	Kakiuchi et al.	369	59.12	
<i>he</i>	FI	7,018,694	03/28/06	Hosoda et al.	428	64.1	
<i>he</i>	FJ	2001/0012257	08/09/01	Suzuki et al.	369	94	

FOREIGN PATENT DOCUMENTS						
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<i>he</i>	FK	2000-187842	07/04/00	JP (+ Abstract in English)		
<i>he</i>	FL	2000-187884	07/04/00	JP (+ Abstract in English)		
<i>he</i>	FM	2000-222764	08/11/00	JP (+ Abstract in English)		
<i>he</i>	FN	1 028 421 A2	08/16/00	EP		
<i>he</i>	FO	2000-285509	10/13/00	JP (+ Abstract in English)		
<i>he</i>	FP	2000-297365	10/24/00	JP (+ Abstract in English)		
<i>he</i>	FQ	2001-155380	06/08/01	JP (+ Abstract in English)		
<i>he</i>	FR	2001-222819	08/17/01	JP (+ Abstract in English)		

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>u</i>	GA	2001/0017833	08/30/01	Yamada et al.	369	59.11	
<i>u</i>	GB	2001/0044002	11/22/01	Shingai et al.	428	64.4	
<i>u</i>	GC	2001/0044073	11/22/01	Fukano et al.	430	270.12	
<i>u</i>	GD	2002/0060979	05/23/02	Tsukuda et al.	369	275.4	
<i>u</i>	GE	2002/0076646	06/20/02	Zhou et al.	430	270.13	
<i>u</i>	GF	2003/0081523	05/01/03	Miyagawa et al.	369	59.11	
<i>u</i>	GG	2003/0086359	05/08/03	Lee et al.	369	275.3	
<i>u</i>	GH	2003/0165111	09/04/03	Flynn	369	288	
<i>u</i>	GI	2003/0224215	12/04/03	Kondo et al.	429	694 ML	

FOREIGN PATENT DOCUMENTS						
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					YES	NO
<i>u</i>	GJ	2001-243655	09/07/01	JP (+ Abstract in English)		
<i>u</i>	GK	1 154 413 A2	11/14/01	EP		
<i>u</i>	GL	2001-322357	11/20/01	JP (+ Abstract in English)		
<i>u</i>	GM	WO 01/93256 A1	12/06/01	WIPO		
<i>u</i>	GN	2001-344823	12/14/01	JP (+ Abstract in English)		
<i>u</i>	GO	1330368 A	01/09/02	CN		
<i>u</i>	GP	1 172 811 A2	01/16/02	EP		
<i>u</i>	GQ	1 178 472 A2	02/06/02	EP		

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
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	HA	2003/0228539	12/11/03	Hosoda et al.	430	270.13	
	HB	2004/0001418	01/01/04	Shinotsuka et al.	369	111	
	HC	2004/0018334	01/29/04	Nee	428	64.1	
	HD	2004/0076907	04/22/04	Inoue et al.	430	270.12	
	HE	2004/0241581	12/02/04	Kakiuchi et al.	430	270.12	
	HF	2005/0018590	01/27/05	Inoue et al.	369	275.2	
	HG	2005/0018591	01/27/05	Inoue et al.	369	275.2	
	HH	2005/0018592	01/27/05	Inoue et al.	369	275.2	
	HI	2005/0047301	03/03/05	Inoue et al.	369	94	
	HJ	2005/0047302	03/03/05	Inoue et al.	369	94	

FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	HK	2002-104317	04/10/02	JP (+ Abstract in English)		
	HL	2002-120458	04/23/02	JP (+ Abstract in English)		
	HM	1 215 669 A2	06/19/02	EP		
	HN	1365108 A	08/21/02	CN (+ Abstract in English)		
	HO	2002-269808	09/20/02	JP (+ Abstract in English)		
	HP	0 947 351 B1	09/25/02	EP		
	HQ	2002-329348	11/15/02	JP (+ Abstract in English)		
	HR	2003-13201	01/15/03	JP (+ Abstract in English)		

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EXAMINER	DATE CONSIDERED 12/27/06
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\* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).



U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  <b>INFORMATION DISCLOSURE STATEMENT</b> (Use several sheets if necessary)	ATTY. DOCKET NO. 890050.443.	APPLICATION NO. 10/684,981
	APPLICANTS Hiroyasu Inoue et al.	
	FILING DATE October 14, 2003	GROUP ART UNIT 1756

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>u</i>	IA	2005/0047303	03/03/05	Inoue et al.	369	94	
<i>u</i>	IB	2005/0047304	03/03/05	Inoue et al.	369	94	
<i>u</i>	IC	2005/0047305	03/03/05	Inoue et al.	369	94	
<i>u</i>	ID	2005/0048249	03/03/05	Inoue et al.	428	64.4	
<i>u</i>	IE	2005/0052194	03/10/05	Kister et al.	324	755	
<i>u</i>	IF	2005/0074306	04/07/05	Montresor	409	179	
<i>u</i>	IG	2005/0243676	11/03/05	Kato et al.	369	59.11	

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>u</i>	IH	2003-54135	02/26/03	JP (+ Abstract in English)		
<i>u</i>	II	2003-85778	03/20/03	JP (+ Abstract in English)		
<i>u</i>	IJ	2003-178448	06/27/03	JP (+ Abstract in English)		
<i>u</i>	IK	2003-260874	09/16/03	JP (+ Abstract in English)		
<i>u</i>	IL	1 351 230 A2	10/08/03	EP		
<i>u</i>	IM	2003-326848	11/19/03	JP (+ Abstract in English)		
<i>u</i>	IN	2004-20822	01/22/04	JP (+ Abstract in English)		
<i>u</i>	IO	2004-30891	01/29/04	JP (+ Abstract in English)		
<i>u</i>	IP	2004-39177	02/05/04	JP (+ Abstract in English)		
<i>u</i>	IQ	2004-87073	03/18/04	JP (+ Abstract in English)		
<i>u</i>	IR	2004-111004	04/08/04	JP (+ Abstract in English)		
<i>u</i>	IS	2004-158134	06/03/04	JP (+ Abstract in English)		
<i>u</i>	IT	1 139 340 B1	06/16/04	EP		

EXAMINER <i>u</i>	DATE CONSIDERED 12/27/06
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